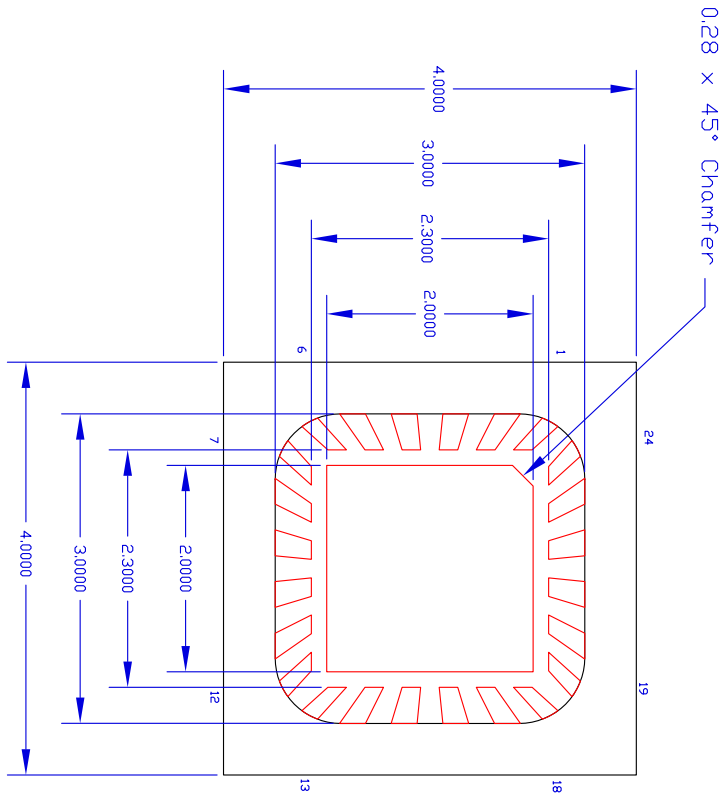
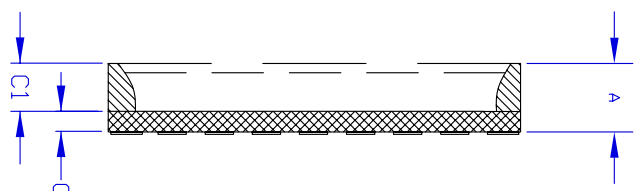


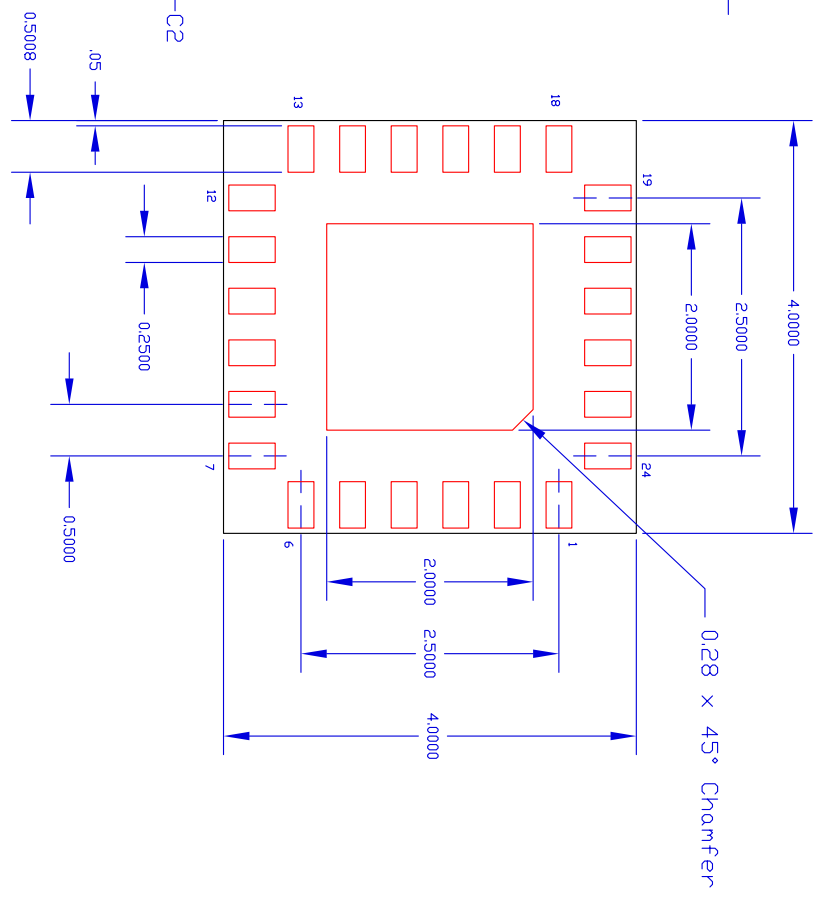
TOP VIEW



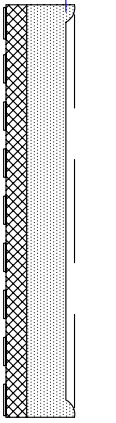
SIDE VIEW



BOTTOM VIEW



Cavity wall  
variance  
0.05~0.15



SIDE VIEW

HEIGHT TABLE

SERIES	C1	C2	A
A-QFN	0.63	0.27	0.90
A-TQFN	0.38	0.27	0.65
TOL	+/- 0.10	+/- 0.05	+/- 0.15

OTHER SIZES AVAILABLE

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Note:

1. Organic substrate
2. Cavity Dam: Hysol FP4451TD
3. Pads: Cu/Ni/Au
4. Copper Thickness: 12µm~18µm (0.5~0.7mil)
5. Bonding Pad Gold Thickness: 1.3µm (50 micro-inch)
6. PCB Pads Gold Thickness: 0.13µm (5 micro-inch)
7. Nickel Thickness: 38µm (150 micro-inch)
8. All Dimensions Are mm

TOLERANCES UNLESS NOTED:		APPROVALS		DATE	
X.XX	±	DRAWN TA		11/29/08	
X.XXX	±				
X.XXXX	±				
ALL DIMENSIONS ARE IN:		MFG		TITLE	
<input type="checkbox"/> INCHES <input type="checkbox"/> MILLIMETERS				<b>24-LEAD 4MM P=0.50MM</b> <b>A-QFN (AIR) OPEN CAVITY</b>	
THIRD ANGLE PROJECTION:		SCALE		DRAWING NO.	
		NONE		A	
		SIZE		REV	
		A		A	
REVISED		DO NOT SCALE DRAWING		SHEET 1 OF 1	

